A METHOD FOR THE MEASUREMENT OF THE COMPLEX COMPRESSIONAL MODULUS OF THIS LAYERS

J. D. Rogers¹
Sandia National Laboratories
Albuquerque, NM

ABSTRACT

A method has been developed for the direct measurement of the complex compressional modulus of thin layers at low frequencies. The test method utilizes an electrodynamic shaker and a special test fixture which maintains the plane strain state of the thin layer. Preliminary tests have been performed on high damping materials with good results. An improved version of the test fixture is being designed to improve the infinitely distant boundary condition simulation.

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¹Sandia National Laboratories, Division 7544, P.O. Box 5800, Albuquerque, NM 87185, (505) 844-7560